

<b>Notice of References Cited</b>	Application/Control No. 10/020,594	Applicant(s)/Patent Under Reexamination SCHREDL ET AL.	
	Examiner Len Tran	Art Unit 1725	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,093,630	07-2000	Geffken et al.	438/612
	B	US-6,010,060	01-2000	Sarkhel et al.	228/179.1
	C	US-6,046,882	04-2000	Pattanaik et al.	29/878
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 3-291938	12-1991	Japan		
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.